

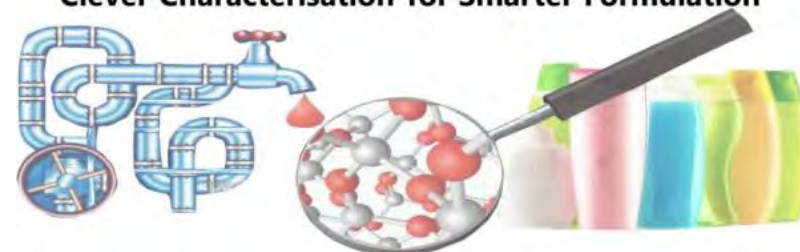


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Royal Society of Chemistry
Burlington House, London
10th November 2017

Clever Characterisation for Smarter Formulation

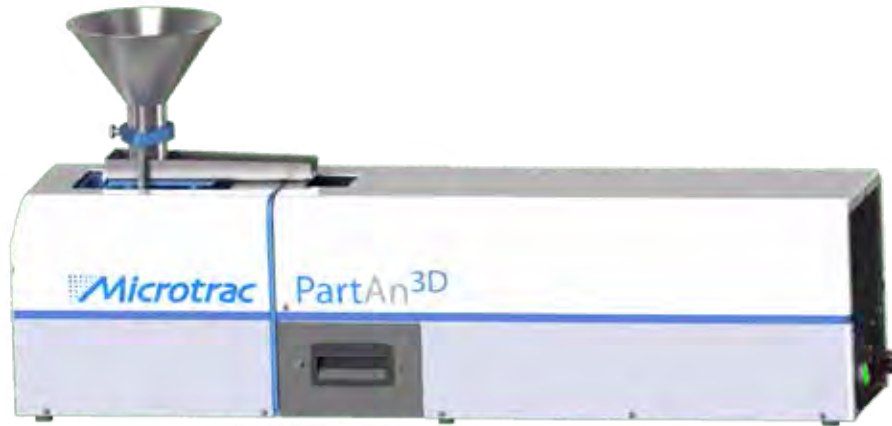


Microtrac
Image Analysis
Particle Size and Shape PartAn SI

Mageleka
Proton NMR measurements of dispersions



Size Range 5 μ m to 1500 μ m



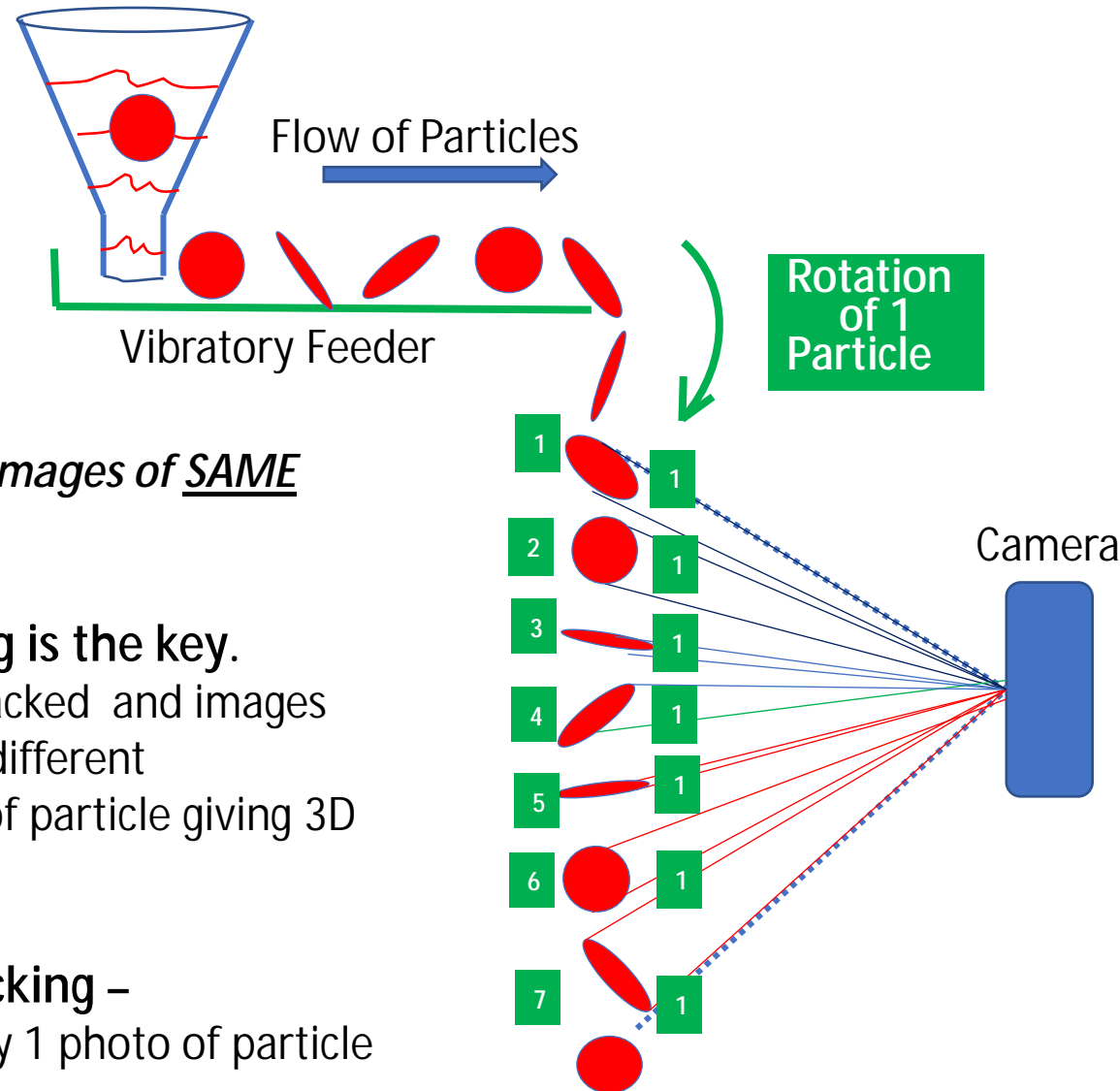
Size Range 4 μ m to 3500 μ m



On Line

Size Range 280 μ m to 127,000 μ m

Microtrac Innovation: Patented 3D measurement technique



3D Multiple images of SAME Particle.

3D - Tracking is the key.

Location is tracked and images obtained for different orientations of particle giving 3D information

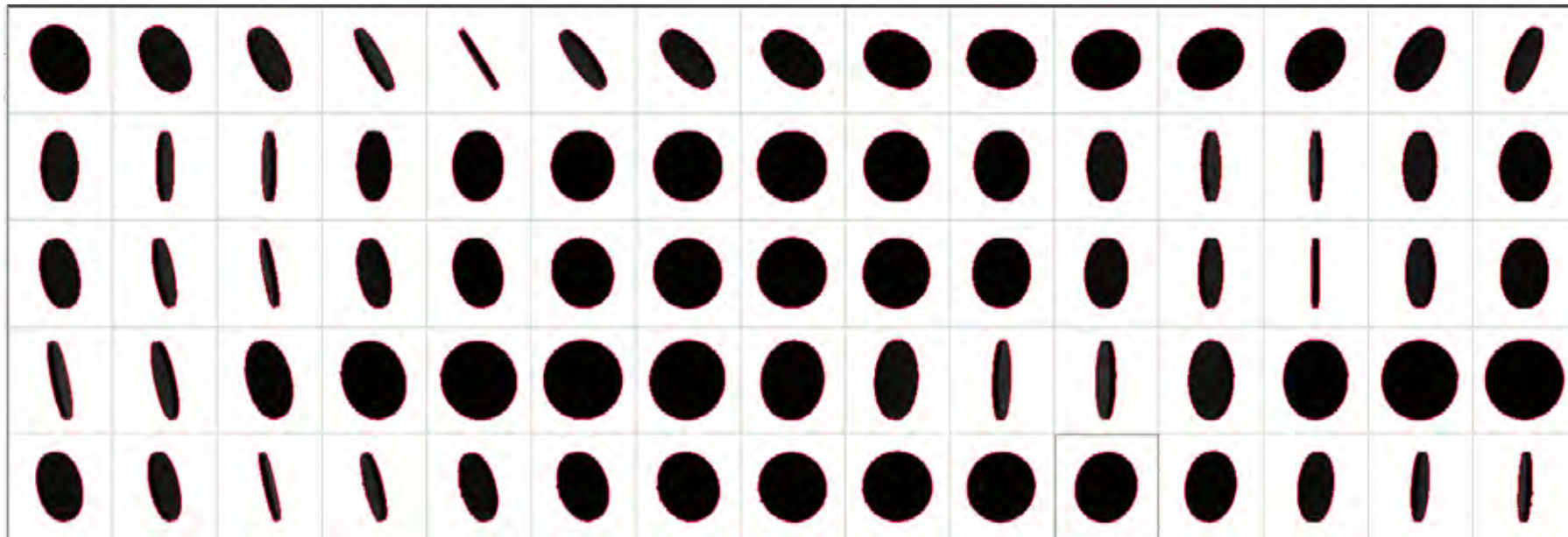
2D - No tracking -

Only 1 photo of particle

3D Image analysis

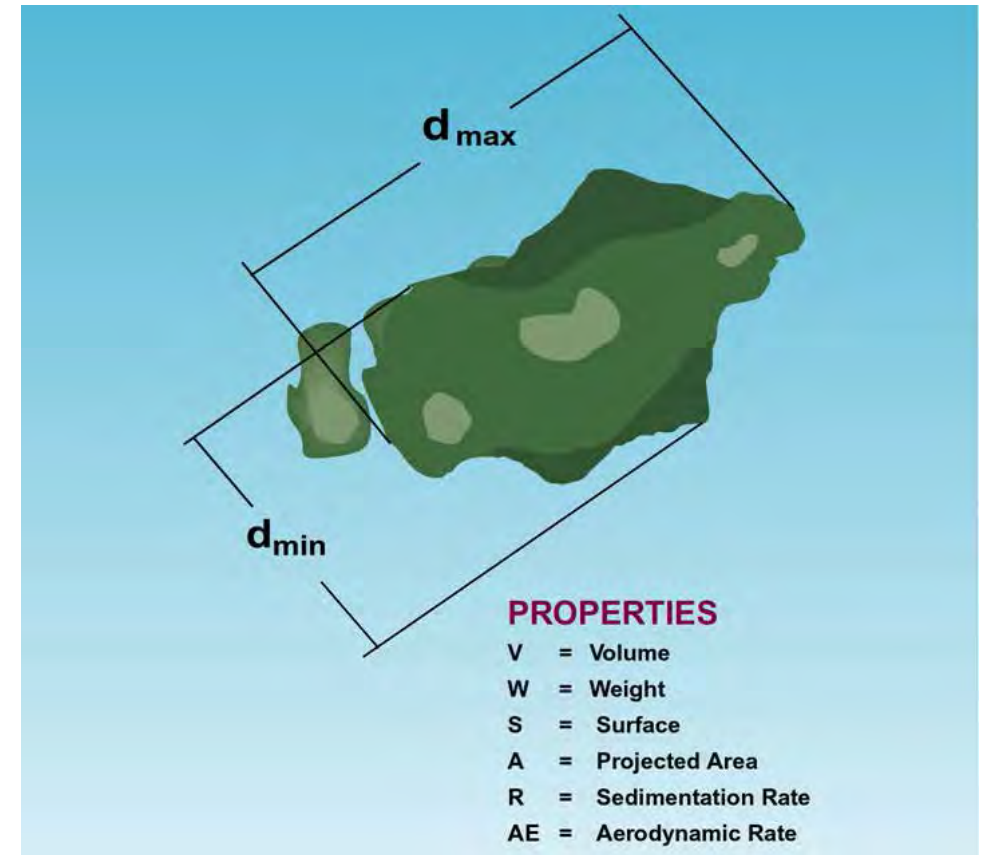
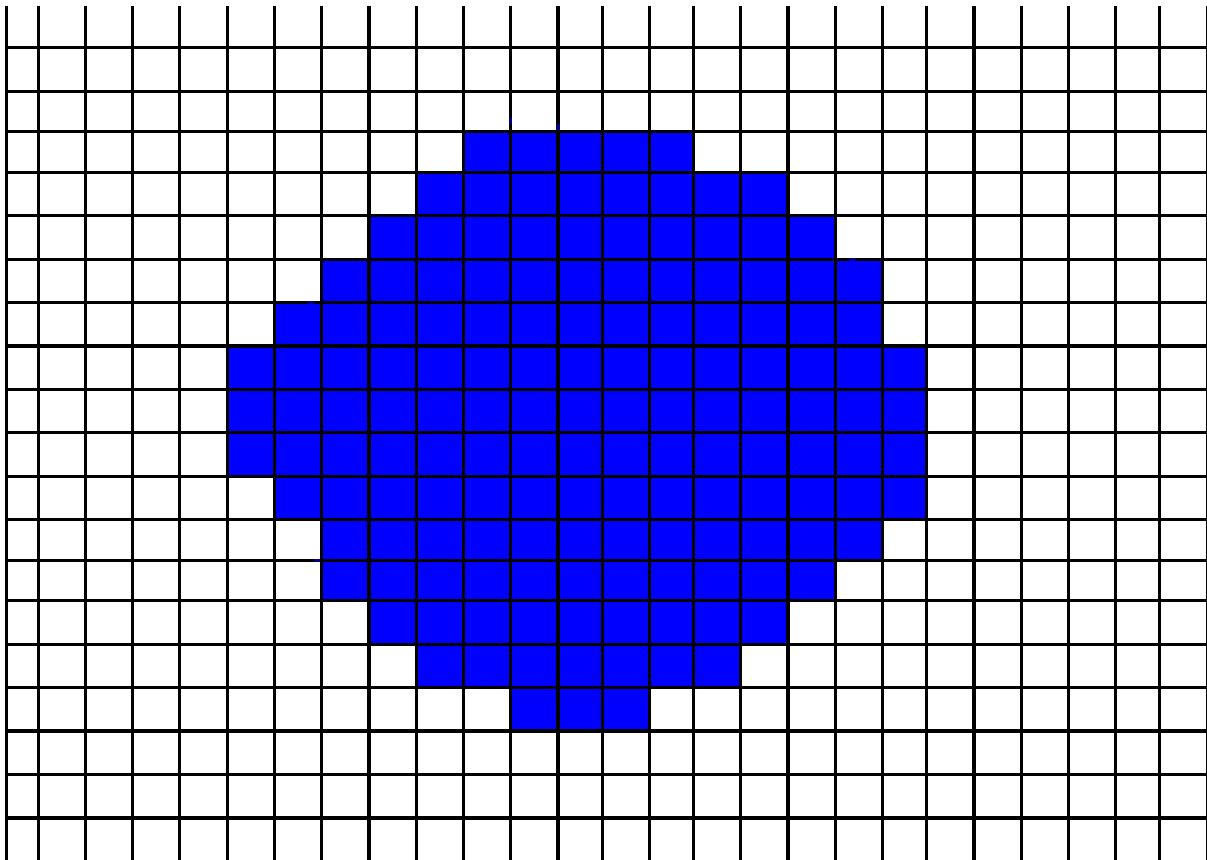
Particles analysed with 3D Image Technology

= = = = = ⇒ Falling direction = = = = = ⇒

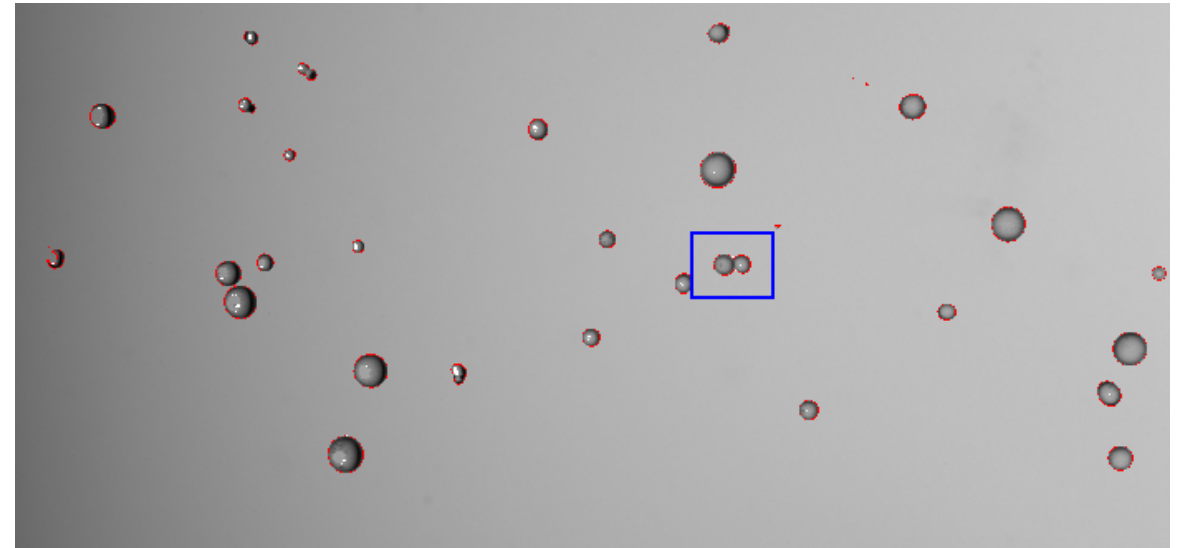
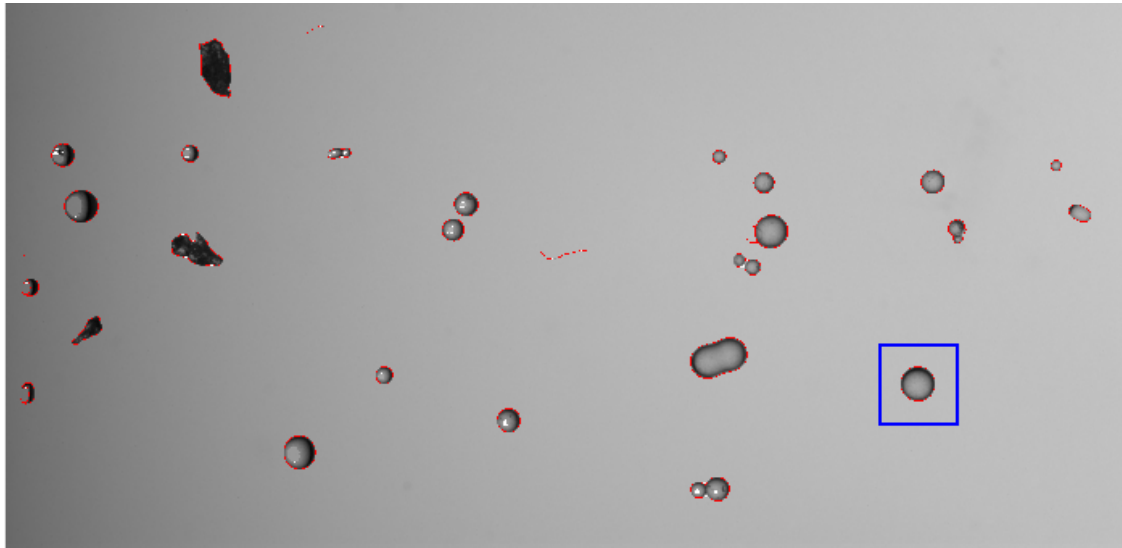


Measurement Principle

The software counts the pixels covered by the particle



Filter Function

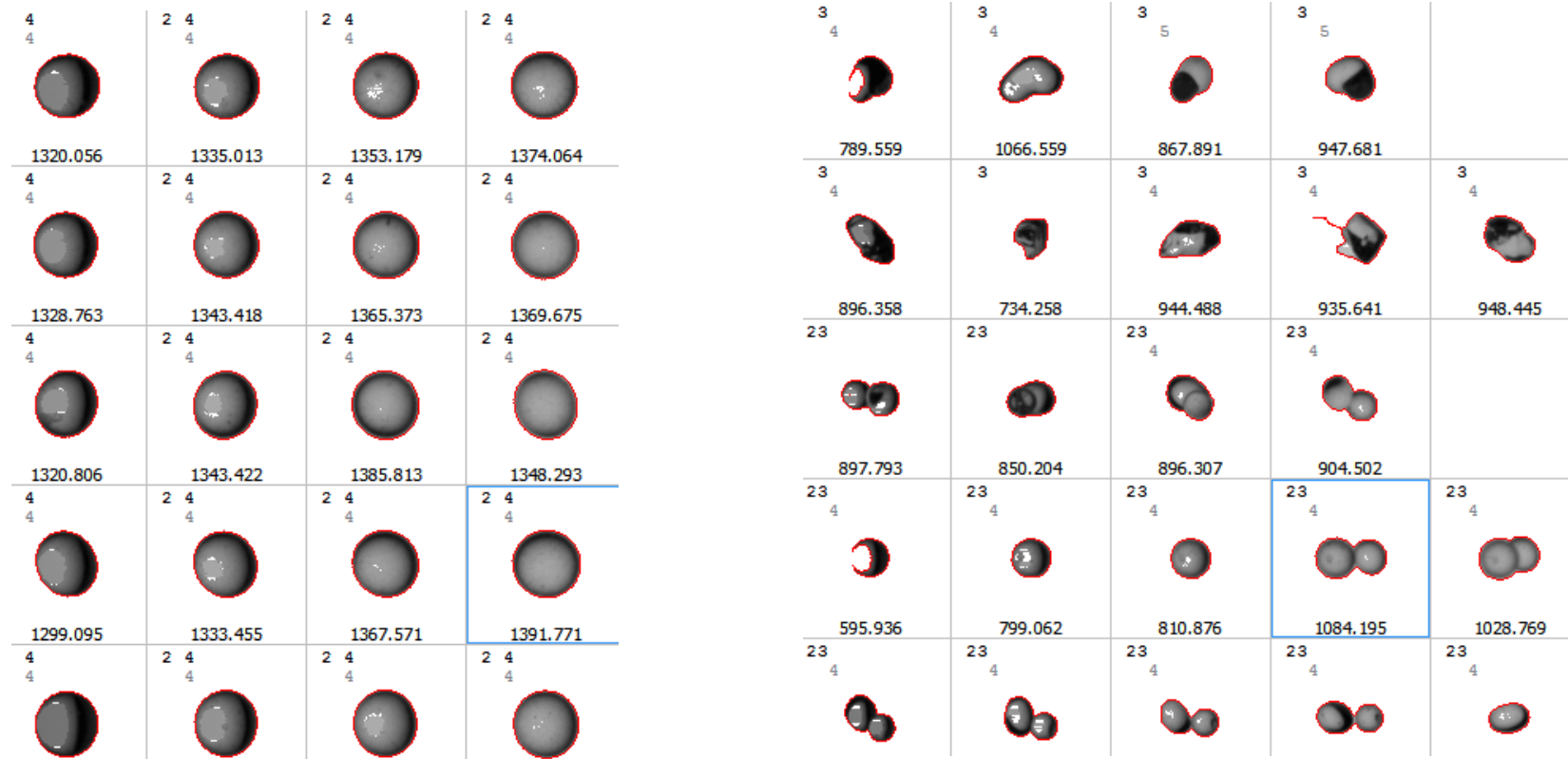


Glass Beads

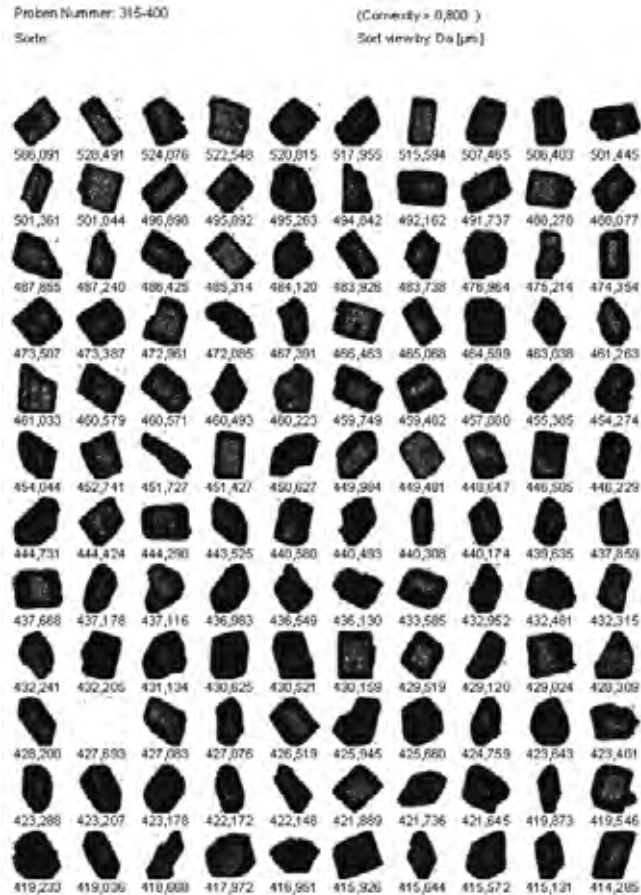
Shape Factors



Good and Bad particle sorted and counted by user defined shapes factors



Results Analysis



Every Particle Measured And Recorded
Available for Further Analysis at a Future Date

The Advantages of 3D Image Analysis (patented by Microtrac)



All three dimensions measured, including Thickness

More accurate volume distributions

Much more accurate size measurements

More accurate shape (sphericity) measurements

Enables accurate reporting of more than
36 morphological parameters

The logo for M Mageleka features a dark blue, jagged, waveform-like graphic on the left that transitions into the letter "M". To the right of the "M" is the name "Mageleka" in a dark brown, sans-serif font.

Private Company formed in 2014 and self funded
Formed by 5 seasoned entrepreneurs with expertise
in electronics, software, nmr, finance and application

MagnoMeter XRS



- New analytical instrument for analysis of complex mixtures
- Measures macroscopic physical characteristics using multi-nuclear nmr
- Separate probe allows use in distant location
- XRS focused on dispersed particle surface area



Techniques



Relaxation

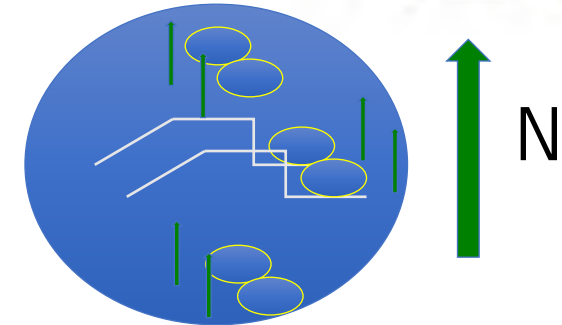
- q particulate analysis
 - q surface area, morphology and surface chemistry
 - q sedimentation and aggregation
- q molecular analysis
 - q polymer complexation and surfactant adsorption
 - q competitive adsorption/desorption
- q **Diffusivity** either continuous or dispersed phase
 - q total aggregate size (complexation)
 - q restrictions to motion (restricted diffusion)
 - q emulsion drop size

T1 AND T2 Pulse Sequences

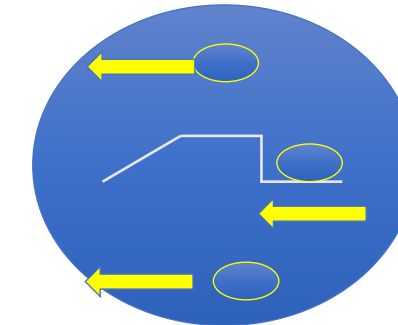
How does it Work?



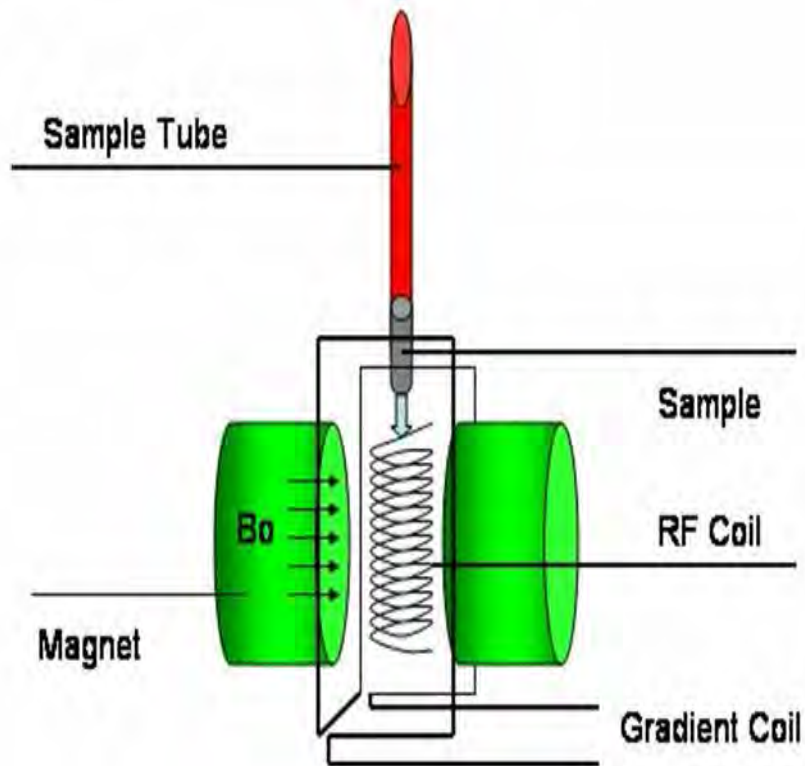
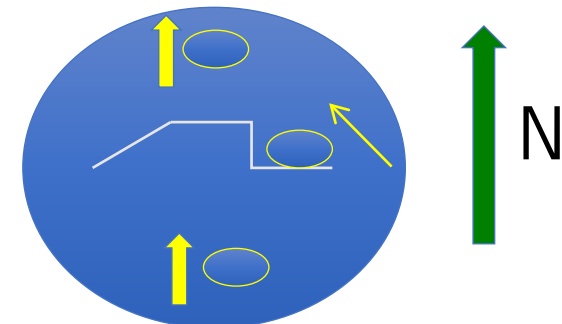
Bound and unbound water in solution



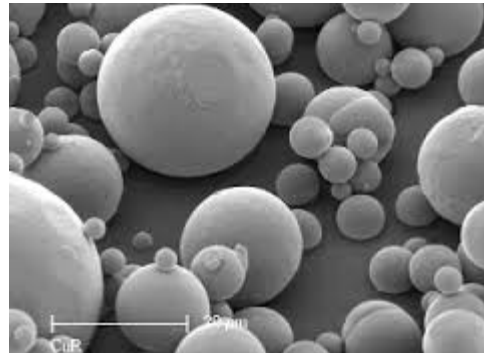
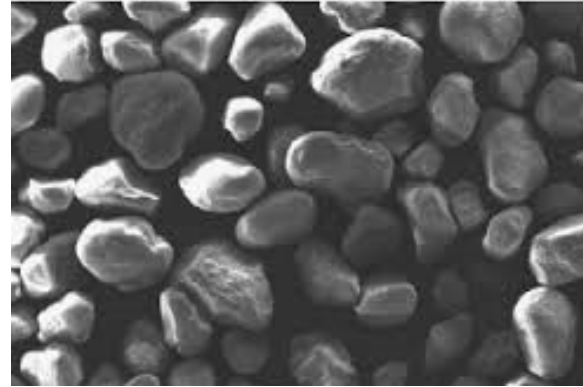
Apply a pulse
Nuclei will then relax
Unbound relax slower



Measure relaxation
Calculate surface area



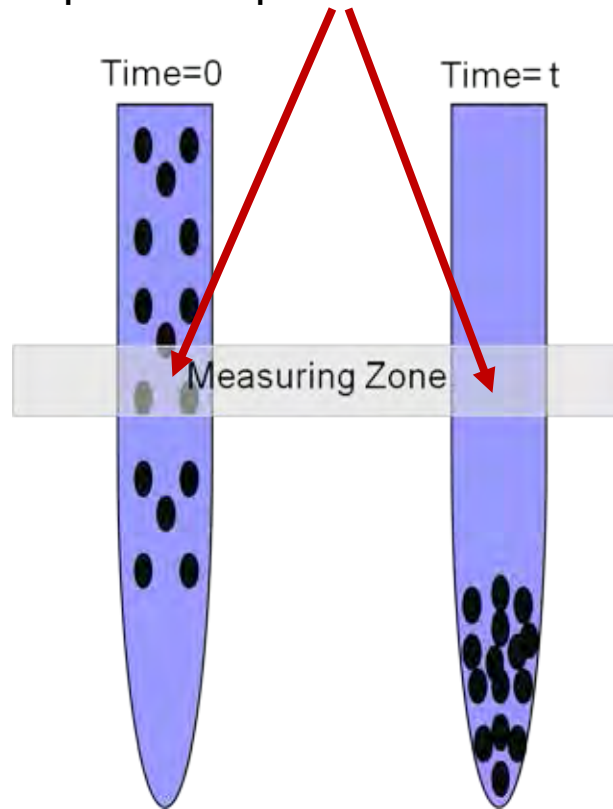
Application: Wetted Surface Area



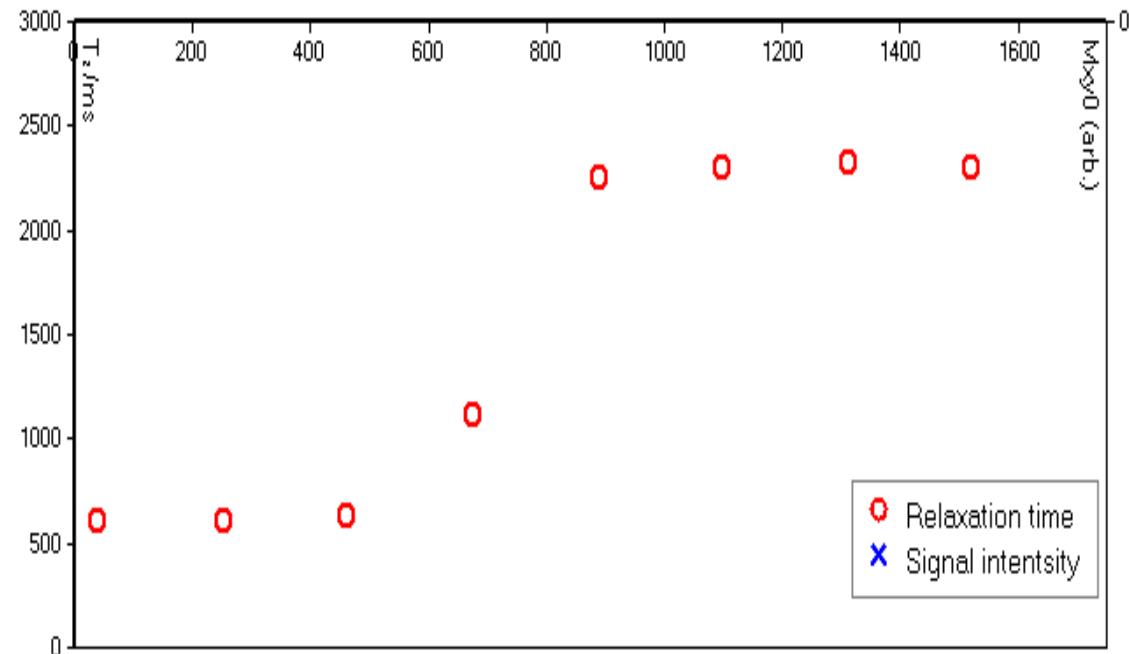
Almost any particle of any size or shape

Application: Sedimentation

Relaxation time increases as settling particles pass out of the measuring zone



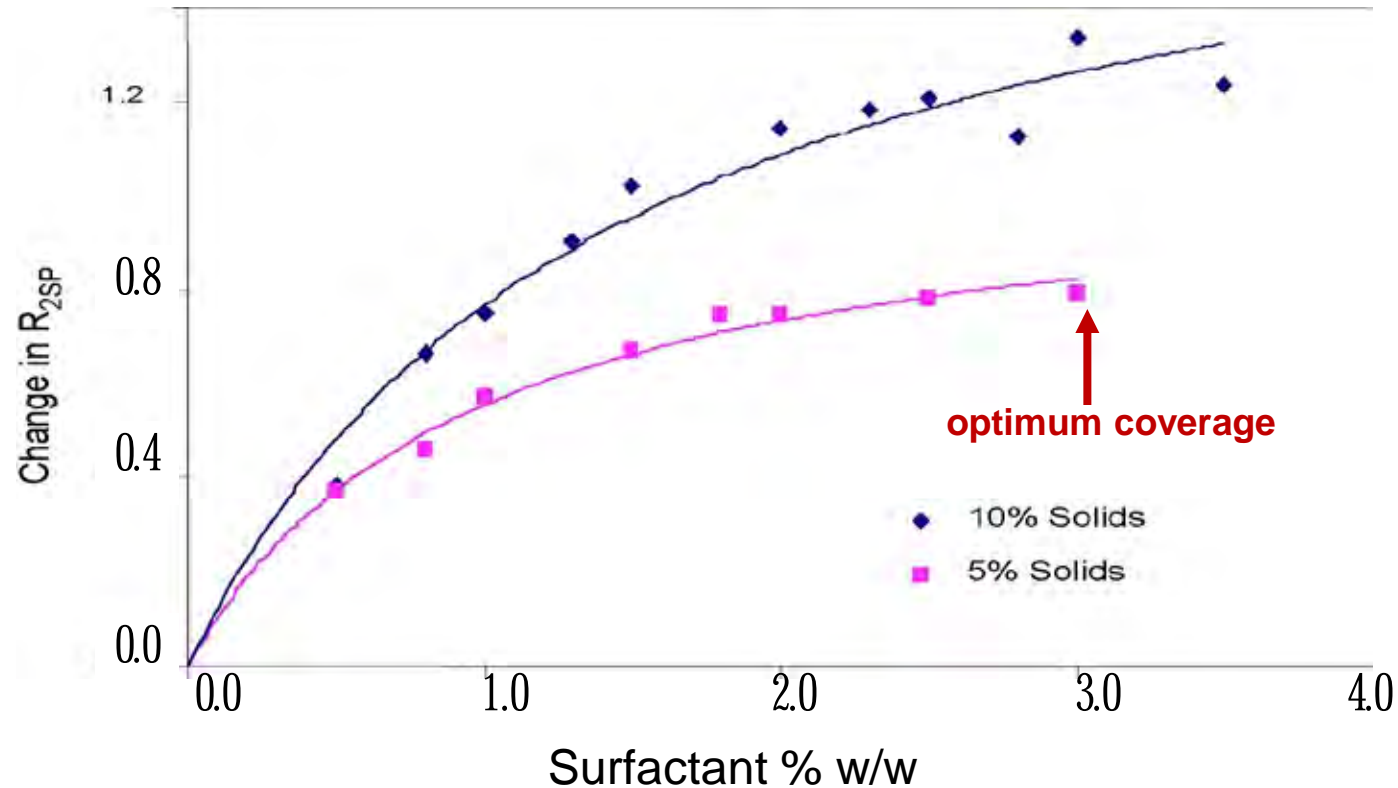
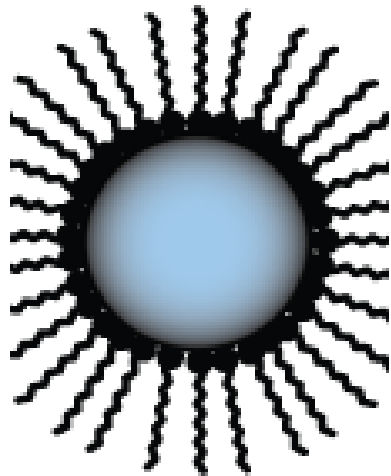
Sedimentation of a 10wt% aqueous suspension of 200nm Barium Titanate



Time mode allows monitoring of suspension stability

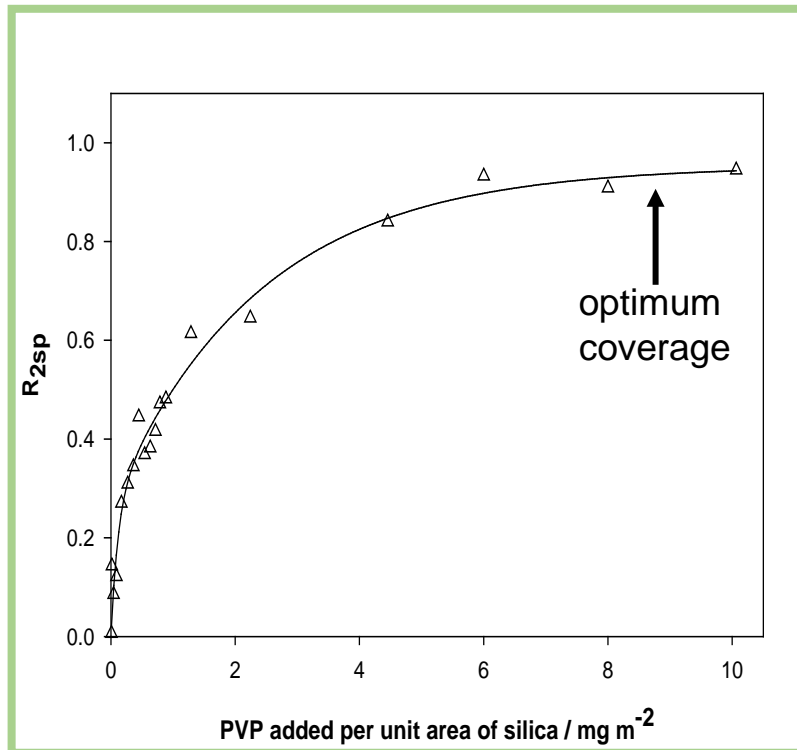
Application: *In situ* Surfactant Adsorption

Particles: 50nm Silica
Surfactant: SDES

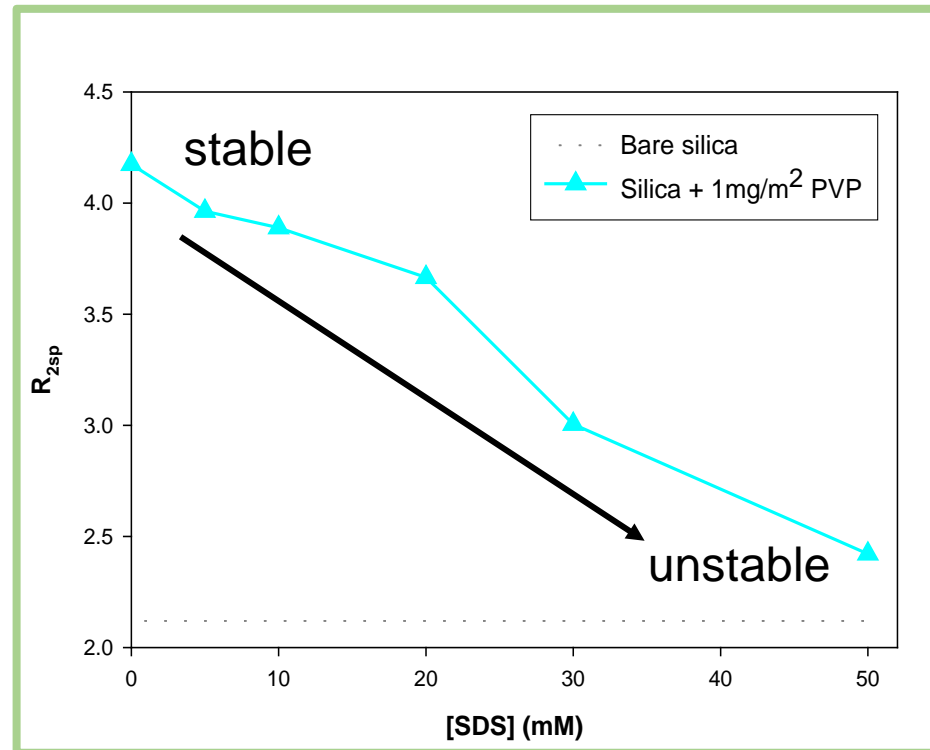


NMR relaxation provides an easy *in-situ* measurement of adsorption onto a surface

Application: Competitive Adsorption of a Surfactant and Polymer onto 15nm Silica



Adsorption of PVP onto bare silica



Desorption of PVP upon addition of SDS

APPLICATIONS



QC application to control batch to batch reproducibility

- Pharmaceutical
- Inks
- Cosmetics
- Sunscreens
- Graphene/Graphite
- Oil and Gas
- Polymer application

Sanderson Technology

Available Techniques



Wetted surface area measurements – Bench Top NMR

Particle Size Distribution - Acoustic Attenuation Spectroscopy

Laser Diffraction, Dynamic Light Scattering

Single Particle Optical Sizing (SPOS)

Zeta Potential – Electrokinetic Sonic Amplitude

Image Analysis

Materials Characterisation, Formulation Consultancy

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